

Notice of References Cited

Application/Control No.

10/616,097

Applicant(s)/Patent Under
Reexamination
SUN ET AL.

Examiner

Edna Wong

CJW/2/05

Art Unit

1753

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0155247	08-2003	Miura et al.	205/157
*	B	US-6,432,821	08-2002	Dubin et al.	438/678
	C	US-6,709,563	03-2004	Nagai et al.	205/123
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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